

### **ABSTRACT OF THE DISCLOSURE**

1           The present invention relates to a process for examining an object, whereby properties of the  
2   object are detected at different times within a spatial frequency space formed by spatial frequencies.  
3   The process is carried out in such a way that consecutive images are recorded in overlapping areas  
4   of the spatial frequency space and, additionally, in areas of the spatial frequency space that differ from  
5   each other.